



PE-B

8 fJ - 150 nJ, Our Lowest Energy Measurements



KEY FEATURES

- 1. VERY LOW NOISE LEVEL**
Take measurements with a noise level as low as 8 fJ with the M-LINK, MAESTRO and S-LINK monitors
- 2. 3 SENSORS AVAILABLE**
 - PE-B-Si family: 3 and 10 mm Ø Silicon sensors for 0.21 to 1.08 μm
 - PE5B-Ge: 5 mm Ø, Germanium sensor for 0.8 to 1.65 μm
 - PE3B-In: 3 mm Ø, InGaAs sensor for 0.9 to 1.7 μm
- 3. SMART INTERFACE**
Containing all the calibration data

AVAILABLE MODELS



PE3B-Si
(3 mm - UV-Silicon)



PE10B-Si
(10 mm - UV-Silicon)



PE5B-Ge
(5 mm - Germanium)



PE3B-In
(3 mm - InGaAs)

ACCESSORIES



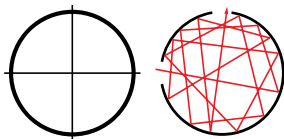
Stand with Delrin Post
(Model Number: 200428)



Fiber Adaptors & Connectors
(FC, ST or SMA)



APM Analog Power Supply
(Model Number: 201848)



IR Alignment Aide, Crosshairs and Integrating Sphere



Pelican Carrying Case

SEE ALSO

TECHNICAL DRAWINGS	118
ABSORPTION CURVES	119
COMPATIBLE MONITORS	
MAESTRO	20
S-LINK	28
M-LINK	32
LIST OF ALL ACCESSORIES	186

APPLICATION NOTE

CALIBRATION UNCERTAINTY OF PHOTO DETECTORS

[202174](#)

MONITORS

ENERGY DETECTORS

POWER DETECTORS

HIGH POWER SOLUTIONS

PHOTO DETECTORS

THZ DETECTORS

OEM DETECTORS

SPECIAL PRODUCTS

BEAM DIAGNOSTICS

PE-B



*Also traceable to NRC-CNRC

SPECIFICATIONS

	PE3B-Si	PE10B-Si	PE5B-Ge	PE3B-In
MAX MEASURABLE ENERGY	30 μ J	150 nJ	3 nJ	300 μ J
EFFECTIVE APERTURE	3 mm \emptyset	10 mm \emptyset	5 mm \emptyset	3 mm \emptyset
MEASUREMENT CAPABILITY				
Spectral Range	210 - 1080 nm	210 - 1080 nm	800 - 1650 nm	900 - 1700 nm
Maximum Measurable Energy				
With M-LINK	30 μ J @ 634 nm	150 nJ @ 634 nm	3 nJ @ 1310 nm	300 μ J @ 1310 nm
With S-LINK	25 μ J @ 634 nm	130 nJ @ 634 nm	2.5 nJ @ 1310 nm	250 μ J @ 1310 nm
With MAESTRO	20 μ J @ 634 nm	110 nJ @ 634 nm	2 nJ @ 1310 nm	200 μ J @ 1310 nm
Noise Equivalent Energy ^a	8 fJ @ 634 nm	1.5 μ J @ 634 nm	1 μ J @ 1310 nm	30 fJ @ 1310 nm
Rise Time (0-100%)	15 μ s	30 μ s	25 μ s	12 μ s
Max Repetition Rate	1000 Hz	1000 Hz	1000 Hz	1000 Hz
Max Pulse Width	10 μ s	10 μ s	10 μ s	10 μ s
Sensitivity	100 GV/J @ 634 nm	20 MV/J @ 634 nm	1 GV/J @ 1310 nm	10 GV/J @ 1310 nm
Calibration Uncertainty ^b	\pm 4% ^c	\pm 8% (210 - 219 nm)	\pm 3.5%	\pm 4% ^d
		\pm 6.5% (220 - 399 nm)		
		\pm 2.5% (400 - 899 nm)		
		\pm 3.5% (900 - 999 nm)		
		\pm 5% (1000 - 1049 nm)		
		\pm 7% (1050 - 1080 nm)		
DAMAGE THRESHOLDS				
Max Energy Density	N/A	5 μ J/cm ²	5 μ J/cm ²	N/A
Max Average Power Density	N/A	65 mW/cm ² @ 532 nm	320 mW/cm ² @ 1064 nm	N/A
PHYSICAL CHARACTERISTICS				
Effective Aperture	3 mm \emptyset	10 mm \emptyset	5 mm \emptyset	3 mm \emptyset
Distance to Sensor Face	13.7 mm	13.7 mm	10.5 mm	N/A
Sensor	UV-Silicon	UV-Silicon	Germanium	InGaAs
Dimensions	38.1 \emptyset x 27.4D mm	38.1 \emptyset x 27.4D mm	38.1 \emptyset x 27.4D mm	38.1 \emptyset x 27.4D mm
Weight	91 g	91 g	91 g	91 g
ORDERING INFORMATION				
Product Name	PE3B-Si	PE10B-Si	PE5B-Ge	PE3B-In
Product Number (Including stand)		202822	202825	
Add Extension for INTEGRA	-INT	-INT	-INT	-INT

Specifications are subject to change without notice

- a. Nominal value. Depends on environmental electromagnetic interference and wavelength.
 b. With Gentec-EO monitor.
 c. This detector is NIST Traceable at the calibration wavelength of 634 nm. Typical values are used at other wavelengths.
 d. This detector is NIST Traceable at the calibration wavelength of 1310 nm. Typical values are used at other wavelengths.